

<b>Notice of References Cited</b>	Application/Control No. 10/633,486		Applicant(s)/Patent Under Reexamination AFAR ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0127579	09-2002	Schiemann et al.	435/6
	B	US-			
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	D	US-			
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	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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